

Supporting Information

Environment-Dependent Radiation Damage in Atmospheric Pressure X-ray Spectroscopy

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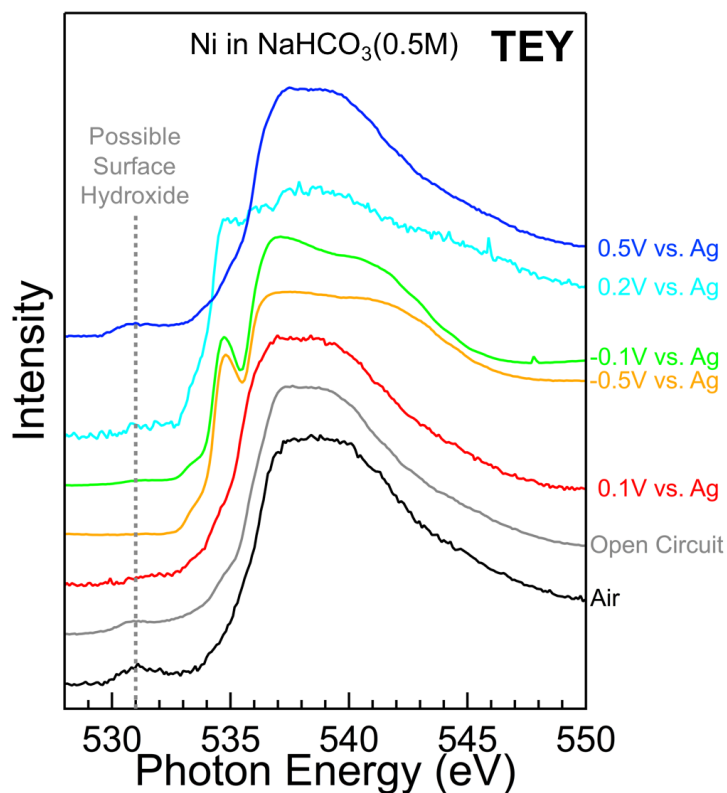


Figure S1. XAS of O K-edge measured with TEY mode for a Ni(50 nm) working electrode in air at atmospheric pressure (black), and in an aqueous NaHCO₃ (0.5 M) solution under open circuit (grey) and while held at the potentials indicated by the colored dots in Figure 1B of the main manuscript. The acquisition time of each spectrum is ~1080s. A small peak is detectable at ~531 eV (vertical dashed line) for all spectra except for that measured at -0.5V, and may be related to the presence of hydroxide at the Ni surface.